

<b>Notice of References Cited</b>	Application/Control No. 10/784,192		Applicant(s)/Patent Under Reexamination CHO ET AL.	
	Examiner Christopher M. Raabe		Art Unit 2879	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,392,338	05-2002	Hori et al.	313/504
	B	US-2001/0002703	06-2001	Koyama, Jun	257/40
	C	US-5,804,917	09-1998	Takahashi et al.	313/504
	D	US-5,307,363	04-1994	Hosokawa et al.	372/53
	E	US-2001/0033136	10-2001	Kawase, Takeo	313/506
	F	US-6,013,538	01-2000	Burrows et al.	438/22
	G	US-2003/0015962	01-2003	Murasko et al.	313/509
	H	US-5,013,141	05-1991	Sakata, Hajime	349/201
	I	US-5,874,803	02-1999	Garbuzov et al.	313/506
	J	US-5,940,568	08-1999	Losch, Kurt	385/129
	K	US-5,994,835	11-1999	Wilson et al.	313/504
	L	US-2003/0164496	09-2003	Do et al.	257/40
	M	US-2003/0071566	04-2003	Kwasnick et al.	313/504

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.